

Claims

- [c1] 1. A testing apparatus, for a flat-panel display comprising at least a plurality of electrode lines and a plurality of driving circuits for driving the electrode lines, the driving circuits being disposed on a first side of the flat-panel display, the testing apparatus comprising:
 - a plurality of switching components, electrically coupled to the electrode lines, wherein the switching components are disposed on a second side of the flat-panel display opposite to the first side thereof; and
 - at least a shorting bar electrically coupled to the switching components.
- [c2] 2. The testing apparatus for the flat-panel display of claim 1, wherein each of the switching components comprises either a diode or at least a TFT.
- [c3] 3. The testing apparatus for the flat-panel display of claim 1, wherein the electrode lines comprise a plurality of data lines.
- [c4] 4. The testing apparatus for the flat-panel display of claim 1, wherein the electrode lines comprise a plurality of scan lines.

[c5] 5. A testing apparatus, for a flat-panel display comprising at least a plurality of electrode lines and a plurality of driving circuits for driving the electrode lines, the testing apparatus comprising:

 a plurality of switching components, each of the switching components comprising a gate, a first source/drain, and a second source/drain, respectively, wherein the first sources/drains are electrically coupled to the electrode lines;

 a switching set electrically coupled to the gates of the switching components; and

 a plurality of shorting bars, each of the shorting bars electrically coupled to the second sources/drains of some of the switching components.

[c6] 6. The testing apparatus for the flat-panel display of claim 5, wherein when the switching set comprises a plurality of switching lines, each of the switching lines are electrically coupled to the gates of some of the switching components.

[c7] 7. The testing apparatus for the flat-panel display of claim 5, wherein each of the switching components comprises at least one TFT.

[c8] 8. The testing apparatus for the flat-panel display of

claim 5, wherein the electrode lines comprise a plurality of data lines.

- [c9] 9. The testing apparatus for the flat-panel display of claim 5, wherein the electrode lines comprise a plurality of scan lines.
- [c10] 10. A testing apparatus, for a flat-panel display comprising at least a plurality of electrode lines and a plurality of driving circuits for driving the electrode lines, and the testing apparatus comprising:
 - a plurality of switching components, each of the switching components comprising a gate, a first source/drain, and a second source/drain, respectively, and the first sources/drains being electrically coupled to the electrode lines;
 - a plurality of switching lines, electrically coupled to the gates of the switching components, and each of the switching lines electrically coupled to the gates of some of the switching components; and
 - a shorting bar, electrically coupled to the second sources/drains of the switching components.
- [c11] 11. The testing apparatus for the flat-panel display of claim 10, wherein each of the switching components comprises at least one TFT.

- [c12] 12. The testing apparatus for the flat-panel display of claim 10, wherein the electrode lines comprise a plurality of data lines.
- [c13] 13. The testing apparatus for the flat-panel display of claim 10, wherein the electrode lines comprise a plurality of scan lines.
- [c14] 14. A testing apparatus, for a flat-panel display comprising at least a plurality of electrode lines and a plurality of driving circuits for driving the electrode lines, and the testing apparatus comprising:
 - a plurality of switching components, electrically coupled to the electrode lines; and
 - a shorting bar set, electrically coupled to the switching components.
- [c15] 15. The testing apparatus for the flat-panel display of claim 14, wherein when the shorting bar set comprises a plurality of shorting bars, each of the shorting bars are electrically coupled to some of the switching components.
- [c16] 16. The testing apparatus for the flat-panel display of claim 14, wherein each of the switching components comprises a diode.
- [c17] 17. The testing apparatus for the flat-panel display of

claim 14, wherein the electrode lines comprise a plurality of data lines.

[c18] 18. The testing apparatus for the flat-panel display of claim 14, wherein the electrode lines comprise a plurality of scan lines.